

<b>Notice of References Cited</b>	Application/Control No. 10/687,233		Applicant(s)/Patent Under Reexamination RUNTE ET AL.	
	Examiner Qing Chen		Art Unit 2191	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Succi et al., "Compatibility, Standards, and Software Production," December 1998, ACM, pg. 140-146.
	V	McCamant et al., "Predicting Problems Caused by Component Upgrades," September 2003, ACM, pg. 287-296.
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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